### MILITARY SPECIFICATION SHEET

# ELECTRON TUBE, RECEIVING

TYPE 125K7Y 1/

The complete requirements for procuring the electron tube described herein shall consist of this document and the latest issue of Specification MIL-E-1.

This specification is mandatory for use by all Departments and Agencies of the Department of Defense.

DESCRIPTION:	Pentoc	Pentode, rf remote cutoff												
©	Outline	•		8-1	(EIA)									
	Base	Base B8-21 (low-loss phenolic)												
	Envelope			MT	MT8									
	Cathoo	le		Coa	Coated unipotential									
	Base o	onnect	ions:											
		n No. ement		1 sh	2 h	3 g3	4 g1	5 k	6 g2	7 8 h a				
ABSOLUTE-MAX	MUMI	RATIN	GS:								_			
•									©	)	©			
Parameter; Unit: Maximum; Minimum;		Ef V 13. 8 11. 4	Eb Vdc 330	Ec1 Vdc		Ec3 Vdc	Pp W 4.4	Ŵ	v	Meg	Alt ft (See note 1)			
TEST CONDITIO	NS (1):	12. 6	250	-3	100	0					**-			
TEST CONDITIO	NS (2):	12. 6	28	0	28	0		*		2				

# GENERAL:

Qualification - Required

1' See note 4

<sup>(</sup>C) denotes changes

Quality conformance inspection, part 1  Total grid current  Electrode current (1) (anode)  Transconductance (1)  Emission	Test condition (1) (see note 2)  Test condition (1)  Test condition (1)  Eb = Ec1 = Ec2 = Ec3 = 30 Vdc	0.65	II II	Ic1	0 : : 6.5	-1. 0	μAdc
inspection, part 1  Total grid current  Electrode current (1) (anode)  Transconductance (1)  Emission	(see note 2)  Test condition (1)  Test condition (1)  [Eb = Ec1 = Ec2 =	0.65		:	:		μ <b>A</b> dc
Electrode current (1) (anode) Transconductance (1) Emission	(see note 2)  Test condition (1)  Test condition (1)  [Eb = Ec1 = Ec2 =	0.65		:	:		μAdc
(anode) Transconductance (1) Emission	Test condition (1)    Eb = Ec1 = Ec2 =	!	11	; Ib			
Emission	Eb = Ec1 = Ec2 =	0.65			0.5	12.0	mAdc
		1 1	п	Sm	1,600	2,400	μmhos
Chart and diseased and	(see note 2)	0.65	п	Is	65		mAdc
Short and discontinuity detection		0,4	п				
Quality conformance inspection, part 2							
Low-frequency vibration	Test condition (1); Rp = 2,000 ohms		•••	Ep		100	mVac
Heater current				If	138	162	mA
Heater-cathode leakage	<i>I</i>			Ihk		20	μAdc
Electrode current (2) (anode)	Test condition (2)			Ib	1.3	2.6	mAdc
Electrode current (1) (screen)	Test condition (1)			lc2	1.6	3.4	mAdc
Electrode current (2) (screen)	Test condition (2)			Ic2	0.35	1.0	mAdc
Transconductance (2)	Test condition (1) Ec1 = -35 Vdc			Sm	1	30	μmhos
Transconductance (3)	Test condition (2); Esig = 0.05 V (see note 3)			Sm	950	1, 450	μ mhos
Direct-interelectrode capacitance	Without shield Without shield Without shield	}		Cglp Cin Cout	3.8 5.2	0.0035 6.2 8.8	pF pF pF
Secureness of base, cap, or insert							
Insulation of electrodes							
Permanence of marking					 		
Quality conformance inspection, part 3							
Life-test provisions	Group A; Ehk = 100 V						
Life-test end point (500 hours)	Transconductance (1)			Sm	1, 300		μmhos
	Low-frequency vibration  Heater current  Heater-cathode leakage  Electrode current (2) (anode)  Electrode current (2) (screen)  Transconductance (2)  Transconductance (3)  Direct-interelectrode capacitance  Secureness of base, cap, or insert  Insulation of electrodes  Permanence of marking  Quality conformance inspection, part 3  Life-test provisions  Life-test end point	Low-frequency vibration  Heater current  Heater-cathode leakage  Electrode current (2) (anode)  Electrode current (2) (screen)  Transconductance (2)  Transconductance (3)  Direct-interelectrode capacitance  Secureness of base, cap, or insert  Insulation of electrodes  Permanence of marking  Quality conformance inspection, part 3  Life-test end point  Test condition (1)  Test condition (2)  Test condition (1)  Ect = -35 Vdc  Test condition (2)  Esig = 0.05 V (see note 3)  Without shield Without shield Without shield  Without shield  Group A; Ehk = 100 V  Life-test end point  Transconductance (1)	Inspection, part 2  Low-frequency vibration  Heater current  Heater-cathode leakage  Electrode current (2) (anode)  Electrode current (1) (screen)  Electrode current (2) (screen)  Transconductance (2)  Test condition (1)  Ecl = -35 Vdc  Transconductance (3)  Direct-interelectrode capacitance  Secureness of base, cap, or insert  Insulation of electrodes  Permanence of marking  Quality conformance inspection, part 3  Life-test provisions  Life-test end point  Test condition (2)  Test condition (1)  Ecl = -35 Vdc  Test condition (2):  Esig = 0.05 V (see note 3)  Without shield Without shield  Without shield  Group A; Ehk = 100 V   Life-test end point  Transconductance (1)	Inspection, part 2  Low-frequency vibration  Heater current  Heater-cathode leakage  Electrode current (2) (anode)  Electrode current (1) (screen)  Electrode current (2) (ascreen)  Test condition (1) (ascreen)  Transconductance (2) Test condition (2) (ascreen)  Transconductance (3) Test condition (1) Ec1 = -35 Vdc  Transconductance (3) Test condition (2); Esig = 0.05 V (see note 3)  Direct-interelectrode capacitance  Direct-interelectrode Without shield Without shield Without shield Without shield  Secureness of base, cap, or insert  Insulation of electrodes  Permanence of marking  Quality conformance inspection, part 3  Life-test provisions  Croup A; Ehk = 100 V	Inspection, part 2	Inspection, part 2	Inspection, part 2

# NOTES:

- 1. See "Reduced pressure (altitude) rating", and altitude, maximum peak voltage.
- 2. This test to be performed at the conclusion of the holding period.
- 3. Signal coupled to grid through 1  $\mu$ F capacitor.
- 4. Tube types 6SK7GTY and 12SK7GTY are hereby deleted from this specification sheet. For replacement purposes, use tube type 6SK7WA for tube type 6SK7GTY and 12SK7Y for tube type 12SK7GTY.

#### Custodians:

Army - EL Navy - EC Air Force - 85

### Review activities:

Army - EL Navy -Air Force - 11, 85 DSA - ES

#### User activities:

Army - WC Navy - AS, OS, MC, CG, SH Air Force - 19 Preparing activity:

Navy - EC

Agent: DSA - ES

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